





Fig. 3. The fragment of the digital signal  $x(i\Delta t)$  before filtration and after it.

Thus when using filtration algorithms a problem appears: to recognize false impulses in the signal's binary components. To solve this problem the following algorithm is suggested:  
 if

$$|x((i-1)\Delta t) - x((i+1)\Delta t)| < |x(i\Delta t) - x((i+2)\Delta t)|, \quad (1)$$

then

$$x(i\Delta t) = x((i-1)\Delta t). \quad (2)$$

Validity of formulae (1) and 2 is evident from Fig.3. Let there be four serial signal samples  $x((i-1)\Delta t)$ ,  $x(i\Delta t)$ ,  $x((i+1)\Delta t)$  and  $x((i+2)\Delta t)$  that correspond to points 1, 2, 3 and 4 in Fig. 3 (a). Assume that we have to recognize which of the impulses is false one: the one in point 2 or the one in point. Taking into account that in this case impulse is a short-term and significant shift of the signal we should find which of points 2 and 3 has the closest nearby values. The maximal proximity of the signal values means the minimal modulus of their difference. The nearby points for point 2 (sample  $x(i\Delta t)$ ) are points 1 (sample  $x((i-1)\Delta t)$ ) and 3 (sample  $x((i+1)\Delta t)$ ). The nearby points for point 3 (sample  $x((i+1)\Delta t)$ ) are points 2 (sample  $x(i\Delta t)$ ) and 4 (sample  $x((i+2)\Delta t)$ ).

Thus if the difference modulus of the signal values at points 1 and 3 is less than the difference modulus at points 2 and 4 it means that impulse 2 is real and impulse 3 is false. In Fig 3(a) points 2 and 4 have closer values than 1 and 3. Therefore in this case in Fig. 3(a) impulse 2 is false and 3 is real one.

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